

Search Notes

Application/Control No.

10/767,312

Examiner

David E. Bochna

Applicant(s)/Patent under
Reexamination

JEWETT ET AL.

Art Unit

3679

SEARCHED

Class	Subclass	Date	Examiner
285	141.1	7/21/2005	DB
	139.1		
	139.2		
	139.3		
	204		
	207		
	364		
	353		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR